Serial No. 09/890,143
Docket No. SHIG 19990241
Amendment G Under Rule 116
And Interview Summery

## AMENDMENTS TO THE CLAIMS:

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Please amend claims 28-30 as shown below. This listing of claims will replace all prior versions and listings of claims in the Application:

## Claims 1-7 (canceled)

Claim 8 (previously presented): A method for forming an optical element comprising the steps of:

forming on a substrate a multilayer film consisting of a stack of alternating layers of high refractive index material and low refractive index material to control a phase and an amplitude of emerging rays; and

adjusting a wavefront phase of the emerging rays by cutting away a portion of the multilayer film stack in accordance with an amount of adjustment of the wavefront phase.

Claim 9 (previously presented): A method according to claim 8, wherein the multilayer film stack is formed in a number of cycles larger than that necessary to saturate a reflectance.

Claim 10 (previously presented): A method according to claim 8, wherein cuttingaway of the multilayer film is controlled by detecting a difference in a material that forms the multilayer film stack.

Claim 11 (previously presented): A method for forming an optical element, comprising the steps of:

forming on a substrate a multilayer film consisting of a stack of alternating layers of high refractive index material and low refractive index material in a number of cycles larger than that necessary to saturate a reflectance;

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forming a correction film on the multilayer film; and

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cutting away a portion of the correction film and the multilayer film stack in accordance with an amount of adjustment of a wavefront phase of emerging rays.

## Claims 12-27 (canceled)

Claim 28 (currently amended): A method according to claim 10, wherein a difference in material is detected by monitoring a secondary electronic electron discharge.

Claim 29 (currently amended): A method according to claim 10, wherein a difference in material is detected by monitoring an optional optical change of characteristics.

Claim 30 (currently amended): A method according to claim 29, wherein said optical change of characteristics monitored is a change in an optical constant of visible rays or a change based on ellipsometry.

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